



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application Serial No. .... 10/655,997  
Filing Date ..... September 5, 2003  
Inventor ..... Jon P. Daley  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2822  
Examiner ..... Pamela E. Perkins  
Attorney's Docket No. .... MI22-2380  
Customer No. .... 021567  
Title: Methods of Forming Patterned Photoresist Layers Over Semiconductor  
Substrates

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

References - See Attached Form PTO-1449

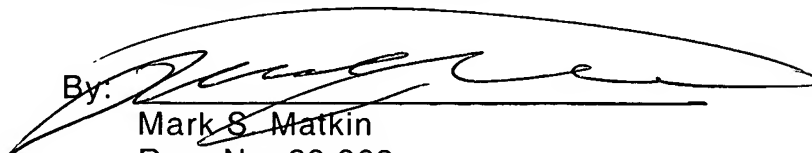
The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art are attached. No admission is made regarding whether all the submitted references are prior art.

Citation of these references is respectfully requested.

A check in the amount of \$180.00 is enclosed to cover the fee specified under 37 C.F.R. § 1.17(p).

Respectfully submitted,

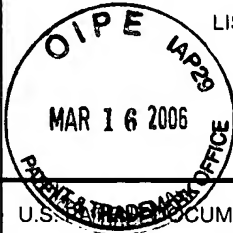
Dated: 3-16-06

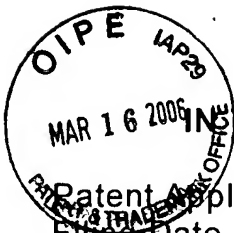
By:   
Mark S. Matkin  
Reg. No. 32,268

03/21/2006 HADELR1 00000047 10655997

01 FC:1805

180.00 DP

|  |    |  |       |                                  |       |                          |                               |
|--|----|--|-------|----------------------------------|-------|--------------------------|-------------------------------|
| Form PTO-1449  |    | U.S. DEPARTMENT OF COMMERCE<br>PATENT AND TRADEMARK OFFICE |       | ATTY. DOCKET NO.<br>MI22-2380    |       | SERIAL NO.<br>10/655,997 |                               |
|  <p>LIST OF ART CITED BY APPLICANT<br/>(Use several sheets if necessary)</p>  |    |  |       | APPLICANT: Jon P. Daley          |       |                          |                               |
|  |    |  |       | FILING DATE<br>September 5, 2003 |       | GROUP ART UNIT<br>2822   |                               |
| U.S. PATENT DOCUMENTS  |    |  |       |                                  |       |                          |                               |
| *Examiner's<br>Initials  | AA | Document<br>Number   | Date  | Name                             | Class | Subclass                 | Filing Date<br>If Appropriate |
|  | AA | 6,838,363  | 01/05 | Wieczorek et al.                 |       |                          |                               |
|  | AB |  |       |                                  |       |                          |                               |
|  | AC |  |       |                                  |       |                          |                               |
|  | AD |  |       |                                  |       |                          |                               |
|  | AE |  |       |                                  |       |                          |                               |
|  | AF |  |       |                                  |       |                          |                               |
|  | AG |  |       |                                  |       |                          |                               |
|  | AH |  |       |                                  |       |                          |                               |
|  | AI |  |       |                                  |       |                          |                               |
| FOREIGN PATENT DOCUMENTS   |    |  |       |                                  |       |                          |                               |
|  |    | Document<br>Number   | Date  | Country                          | Class | Subclass                 | Translation                   |
|  |    |  |       |                                  |       |                          | Yes No                        |
|  | AJ |  |       |                                  |       |                          |                               |
|  | AK |  |       |                                  |       |                          |                               |
|  | AL |  |       |                                  |       |                          |                               |
| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)  |    |  |       |                                  |       |                          |                               |
|  | AM |  |       |                                  |       |                          |                               |
|  |    |  |       |                                  |       |                          |                               |
|  |    |  |       |                                  |       |                          |                               |
|  | AN |  |       |                                  |       |                          |                               |
|  |    |  |       |                                  |       |                          |                               |
|  |    |  |       |                                  |       |                          |                               |
|  | AO |  |       |                                  |       |                          |                               |
|  |    |  |       |                                  |       |                          |                               |
|  |    |  |       |                                  |       |                          |                               |
| EXAMINER   |    | DATE CONSIDERED  |       |                                  |       |                          |                               |
| <p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p> |    |  |       |                                  |       |                          |                               |



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application Serial No. ....10/655,997  
Filing Date ..... September 5, 2003  
Inventor ..... Jon P. Daley  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2822  
Examiner ..... Pamela E. Perkins  
Attorney's Docket No. .... MI22-2380  
Customer No. .... 021567  
Title: Methods of Forming Patterned Photoresist Layers Over Semiconductor  
Substrates

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

References - See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed before the mailing of a first office action after the filing of a Request for Continued Examination. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Dated: 12-1-05

By. 

Mark S. Matkin  
Reg. No. 32,268

**EV633200332**

**EV633262561**

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-2380SERIAL NO.  
10/655,997LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Jon P. Daley

FILING DATE  
September 5, 2003GROUP ART UNIT  
2822

## U.S. PATENT DOCUMENTS

| *Examiner's<br>Initials |    | Document<br>Number | Date    | Name             | Class | Subclass | Filing Date<br>If Appropriate |
|-------------------------|----|--------------------|---------|------------------|-------|----------|-------------------------------|
|                         | AA | 3,772,101          | 11/1973 | Chumbres et al.  |       |          |                               |
|                         | AB | 5,677,102          | 10/1997 | Shihara          |       |          |                               |
|                         | AC | 6,096,634          | 08/2000 | Nguyen           |       |          |                               |
|                         | AD | 6,165,834          | 12/2000 | Agarwal et al.   |       |          |                               |
|                         | AE | 6,188,097          | 02/2001 | Derderian et al. |       |          |                               |
|                         | AF | 6,238,994          | 05/2001 | Derderian et al. |       |          |                               |
|                         | AG | 6,255,035          | 07/2001 | Minter et al.    |       |          |                               |
|                         | AH | 6,297,527          | 10/2001 | Agarwal et al.   |       |          |                               |
|                         | AI | 6,376,149          | 04/2002 | Grober et al.    |       |          |                               |

## FOREIGN PATENT DOCUMENTS

|  |    | Document<br>Number | Date | Country | Class | Subclass | Translation |    |
|--|----|--------------------|------|---------|-------|----------|-------------|----|
|  |    |                    |      |         |       |          | Yes         | No |
|  | AJ |                    |      |         |       |          |             |    |
|  | AK |                    |      |         |       |          |             |    |
|  | AL |                    |      |         |       |          |             |    |

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

|  |    |  |  |
|--|----|--|--|
|  | AM |  |  |
|  | AN |  |  |
|  | AO |  |  |

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

|   |  |  |  |                                  |                          |
|---|--|--|--|----------------------------------|--------------------------|
| Form PTO-1449   |  | U.S. DEPARTMENT OF COMMERCE<br>PATENT AND TRADEMARK OFFICE |  | ATTY. DOCKET NO.<br>MI22-2380    | SERIAL NO.<br>10/655,997 |
| LIST OF ART CITED BY APPLICANT<br>(Use several sheets if necessary) |  |  |  | APPLICANT: Jon P. Daley          |                          |
|   |  |  |  | FILING DATE<br>September 5, 2003 | GROUP ART UNIT<br>2822   |

| U.S. PATENT DOCUMENTS |    |                 |         |                  |       |          |                            |
|-----------------------|----|-----------------|---------|------------------|-------|----------|----------------------------|
| *Examiner's Initials  |    | Document Number | Date    | Name             | Class | Subclass | Filing Date If Appropriate |
|                       | AA | 6,399,982       | 06/2002 | Derderian et al. |       |          |                            |
|                       | AB | 6,511,896       | 01/2003 | Basceri et al.   |       |          |                            |
|                       | AC | 6,608,343       | 08/2003 | Derderian et al. |       |          |                            |
|                       | AD | 6,617,250       | 09/2003 | Basceri et al.   |       |          |                            |
|                       | AE | 6,649,466       | 11/2003 | Basceri et al.   |       |          |                            |
|                       | AF | 6,744,093       | 06/2004 | Agarwal et al.   |       |          |                            |
|                       | AG | 6,746,916       | 06/2004 | Agarwal et al.   |       |          |                            |
|                       | AH | 6,777,739       | 08/2004 | Agarwal et al.   |       |          |                            |
|                       | AI | 6,780,766       | 08/2004 | Basceri et al.   |       |          |                            |

| FOREIGN PATENT DOCUMENTS |    |                 |      |         |       |          |             |    |
|--------------------------|----|-----------------|------|---------|-------|----------|-------------|----|
|                          |    | Document Number | Date | Country | Class | Subclass | Translation |    |
|                          |    |                 |      |         |       |          | Yes         | No |
|                          | AJ |                 |      |         |       |          |             |    |
|                          | AK |                 |      |         |       |          |             |    |
|                          | AL |                 |      |         |       |          |             |    |

| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) |    |  |  |
|---|----|--|--|
|   | AM |  |  |
|   |    |  |  |
|   | AN |  |  |
|   |    |  |  |
|   | AO |  |  |
|   |    |  |  |

|          |                 |
|----------|-----------------|
| EXAMINER | DATE CONSIDERED |
|----------|-----------------|

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

|   |  |  |  |                                  |  |                          |  |
|---|--|--|--|----------------------------------|--|--------------------------|--|
| Form PTO-1449   |  | U.S. DEPARTMENT OF COMMERCE<br>PATENT AND TRADEMARK OFFICE |  | ATTY. DOCKET NO.<br>MI22-2380    |  | SERIAL NO.<br>10/655,997 |  |
| LIST OF ART CITED BY APPLICANT<br>(Use several sheets if necessary) |  |  |  | APPLICANT: Jon P. Daley          |  |                          |  |
|   |  |  |  | FILING DATE<br>September 5, 2003 |  | GROUP ART UNIT<br>2822   |  |

| U.S. PATENT DOCUMENTS   |    |                    |         |                |       |          |                               |
|-------------------------|----|--------------------|---------|----------------|-------|----------|-------------------------------|
| *Examiner's<br>Initials |    | Document<br>Number | Date    | Name           | Class | Subclass | Filing Date<br>If Appropriate |
|                         | AA | 6,817,086          | 11/2004 | Lu et al.      |       |          |                               |
|                         | AB | 6,900,497          | 05/2005 | Agarwal et al. |       |          |                               |
|                         | AC |                    |         |                |       |          |                               |
|                         | AD |                    |         |                |       |          |                               |
|                         | AE |                    |         |                |       |          |                               |
|                         | AF |                    |         |                |       |          |                               |
|                         | AG |                    |         |                |       |          |                               |
|                         | AH |                    |         |                |       |          |                               |
|                         | AI |                    |         |                |       |          |                               |

| FOREIGN PATENT DOCUMENTS |    |                    |      |         |       |          |             |    |
|--------------------------|----|--------------------|------|---------|-------|----------|-------------|----|
|                          |    | Document<br>Number | Date | Country | Class | Subclass | Translation |    |
|                          |    |                    |      |         |       |          | Yes         | No |
|                          | AJ |                    |      |         |       |          |             |    |
|                          | AK |                    |      |         |       |          |             |    |
|                          | AL |                    |      |         |       |          |             |    |

| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) |    |  |  |
|---|----|--|--|
|   | AM |  |  |
|   |    |  |  |
|   | AN |  |  |
|   |    |  |  |
|   | AO |  |  |
|   |    |  |  |

|          |                 |
|----------|-----------------|
| EXAMINER | DATE CONSIDERED |
|----------|-----------------|

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.